

LINEAR SYSTEMS

Twenty-Five Years Of Quality Through Innovation

FEATURES

Improved Replacement for SILICONIX, FAIRCHILD, & NATIONAL: 2N5911 & 2N5912

LOW NOISE (10kHz) $e_n \sim 4nV/\sqrt{Hz}$

HIGH TRANSCONDUCTANCE (100MHz) $g_{fs} \geq 4000\mu S$

ABSOLUTE MAXIMUM RATINGS¹

@ 25 °C (unless otherwise stated)

Maximum Temperatures

Storage Temperature -55 to +150 °C

Operating Junction Temperature -55 to +150 °C

Maximum Power Dissipation

Continuous Power Dissipation (Total)⁴ 500mW

Maximum Currents

Gate Current 50mA

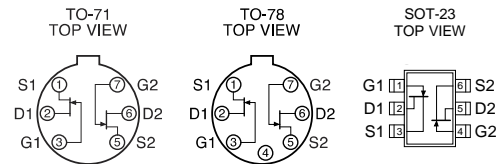
Maximum Voltages

Gate to Drain -25V

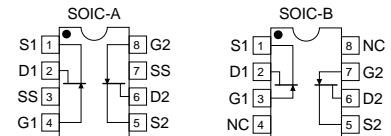
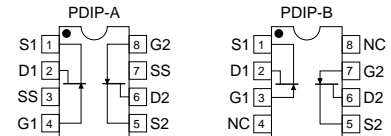
Gate to Source -25V

LS5911 LS5912 LS5912C

IMPROVED LOW NOISE WIDEBAND
MONOLITHIC DUAL N-CHANNEL
JFET AMPLIFIER



TOP VIEW



MATCHING ELECTRICAL CHARACTERISTICS @25 °C (unless otherwise stated)

| SYMBOL | CHARACTERISTIC | TYP | LS5911 | | LS5912 | | LS5912C | | UNIT | CONDITIONS |
|--|---|-----|--------|-----|--------|-----|---------|-----|------------------|---|
| | | | MIN | MAX | MIN | MAX | MIN | MAX | | |
| $ V_{GS1} - V_{GS2} $ | Differential Gate to Source Cutoff Voltage | | | 10 | | 15 | | 40 | mV | $V_{DG} = 10V, I_D = 5mA$ |
| $\frac{\Delta V_{GS1} - V_{GS2} }{\Delta T}$ | Differential Gate to Source Voltage Change with Temperature | | | 20 | | 40 | | 40 | $\mu V/^\circ C$ | $V_{DG} = 10V, I_D = 5mA$ $T_A = -55 \text{ to } +125^\circ C$ |
| $\frac{I_{DSS1}}{I_{DSS2}}$ | Saturation Drain Current Ratio | | 0.95 | 1 | 0.95 | 1 | 0.95 | 1 | | $V_{DS} = 10V, V_{GS} = 0V$ Notes 2, 3 |
| $ I_{G1} - I_{G2} $ | Differential Gate Current | | | 20 | | 20 | | 20 | nA | $V_{DG} = 10V, I_D = 5mA$ $T_A = +125^\circ C$ |
| $\frac{g_{fs1}}{g_{fs2}}$ | Forward Transconductance Ratio | | 0.95 | 1 | 0.95 | 1 | 0.95 | 1 | | $V_{DS} = 10V, I_D = 5mA$ $f = 1kHz^3$ |
| CMRR | Common Mode Rejection Ratio | 85 | | | | | | | dB | $V_{DG} = 5V \text{ to } 10V$ $I_D = 5mA$ |

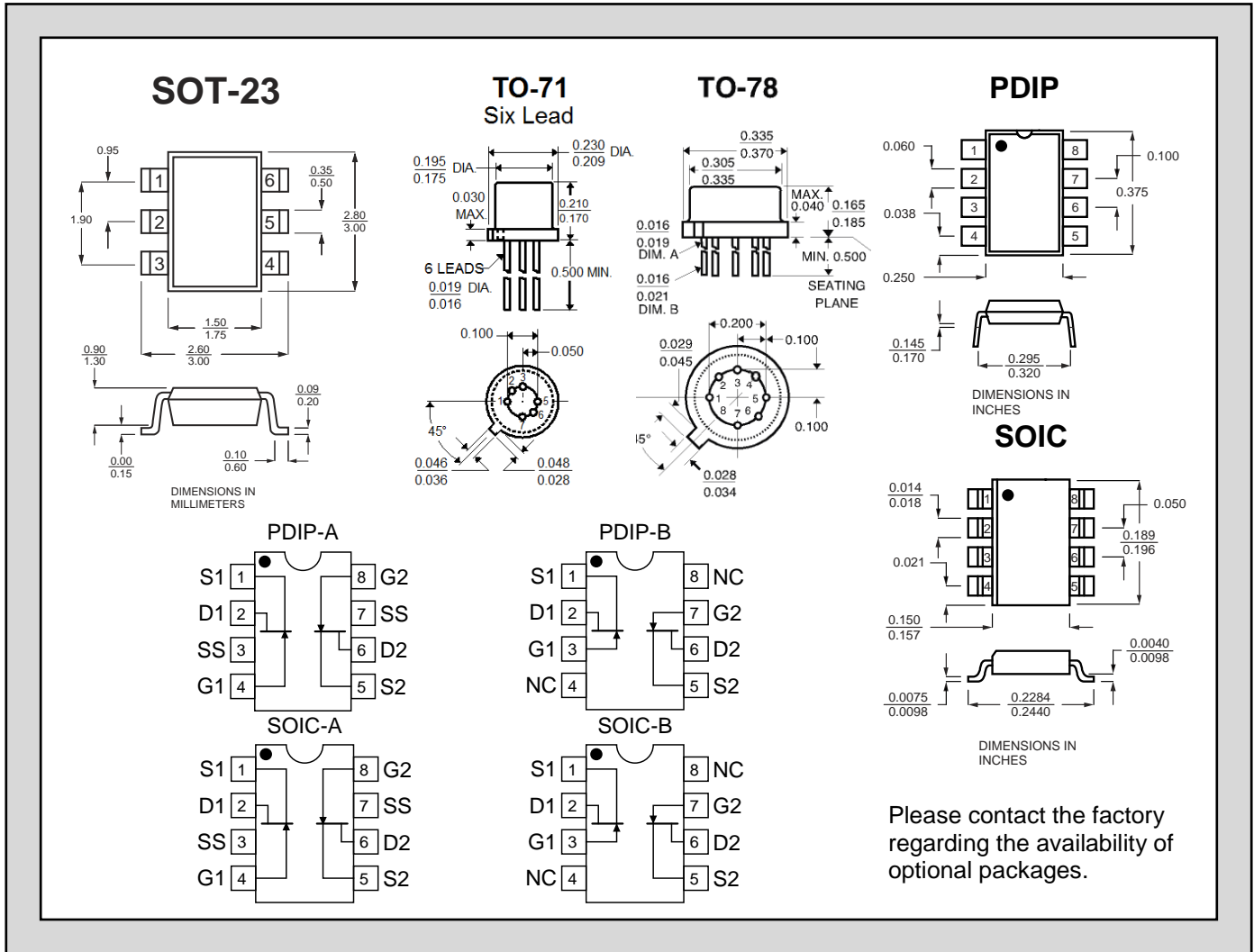
STATIC ELECTRICAL CHARACTERISTICS @25 °C (unless otherwise stated)

| SYM. | CHARACTERISTIC | TYP | LS5911 | | LS5912 | | LS5912C | | UNIT | CONDITIONS |
|---------------|--------------------------------|-----|--------|---------|--------|---------|---------|---------|------|--|
| | | | MIN | MAX | MIN | MAX | MIN | MAX | | |
| BV_{GSS} | Gate to Source Breakdown | | -25 | | -25 | | -25 | | V | $I_G = -1\mu A, V_{DS} = 0V$ |
| $V_{GS(off)}$ | Gate to Source Cutoff Voltage | | -1 | -5 | -1 | -5 | -1 | -5 | | $V_{DS} = 10V, I_D = 1nA$ |
| $V_{GS(F)}$ | Gate to Source Forward Voltage | 0.7 | | | | | | | | $I_G = 1mA, V_{DS} = 0V$ |
| V_{GS} | Gate to Source Voltage | | -0.3 | -4 | -0.3 | -4 | -0.3 | -4 | | $V_{DG} = 10V, I_G = 5mA$ |
| I_{DSS} | Drain to Source Saturation | | 7 | 40 | 7 | 40 | 7 | 40 | mA | $V_{DS} = 10V, V_{GS} = 0V$ |
| I_{GSS} | Gate Leakage Current | -1 | | -50 | | -50 | | -50 | pA | $V_{GS} = -15V, V_{DS} = 0V$ |
| I_G | Gate Operating Current | -1 | | -50 | | -50 | | -50 | | $V_{DG} = 10V, I_D = 5mA$ |
| I_{G1G2} | Gate to Gate Isolation Current | | | ± 1 | | ± 1 | | ± 1 | | $V_{G1} - V_{G2} = \pm 25V, I_D = I_S = 0$ |

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DYNAMIC ELECTRICAL CHARACTERISTICS @25 °C (unless otherwise stated)

| SYM. | CHARACTERISTIC | TYP | LS5911 | | LS5912 | | LS5912C | | UNIT | CONDITIONS | |
|------------------|--------------------------------|-----|------------|------|--------|------|---------|------|--------|--|---|
| | | | MIN | MAX | MIN | MAX | MIN | MAX | | | |
| g _{fs} | Forward Transconductance | | f = 1kHz | 4000 | 10000 | 4000 | 10000 | 4000 | 10000 | μS | V _{DG} = 10V, I _D = 5mA |
| | | | f = 100MHz | 7000 | | | | | | | |
| g _{os} | Output Conductance | | f = 1kHz | | 100 | | 100 | | 100 | pF | V _{DG} = 10V, I _D = 5mA f = 1MHz |
| | | | f = 100MHz | 120 | | | | | | | |
| C _{iss} | Input Capacitance | | | 5 | | 5 | | 5 | pF | V _{DG} = 10V, I _D = 5mA f = 1MHz | |
| C _{rss} | Reverse Transfer Capacitance | | | 1.2 | | 1.2 | | 1.2 | | | |
| NF | Noise Figure | | | 1 | | 1 | | 1 | dB | V _{DG} = 10V, I _D = 5mA f = 10kHz, R _G = 100KΩ | |
| e _n | Equivalent Input Noise Voltage | | f = 100Hz | 7 | 20 | 20 | 20 | 20 | nV/√Hz | V _{DG} = 10V, I _D = 5mA f = 100Hz | |
| | | | f = 10kHz | 4 | 10 | 10 | 10 | 10 | nV/√Hz | V _{DG} = 10V, I _D = 5mA f = 10kHz | |



NOTES

1. Absolute maximum ratings are limiting values above which serviceability may be impaired.
2. Pulse Test: $PW \leq 300\mu s$ Duty Cycle $\leq 3\%$
3. Assumes smaller value in numerator.
4. Derate $4mW/^{\circ}C$ above $25^{\circ}C$.

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